

Notice of References Cited

Application/Control No.

09/931,125

Applicant(s)/Patent Under
Reexamination
ROONEY ET AL.

Examiner

Marshall S Eng

Art Unit

2133

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,588,115	12-1996	Augarten, Michael H.	714/718
	C	US-6,643,807	11-2003	Heaslip et al.	714/719
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schanstra et al., Semiconductor manufacturing process monitoring using built-in self-test for embedded memories, October 1998, International Test Conference proceedings 1998, pp 872-881.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.